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Focusing and Beam Shifting Properties of Fabry-Perot Type Interferometers

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Abstract. The basic formulations of a plane-wave interaction with planar, double and triple-screened interferometers are reviewed and extended to encompass slowly varying, non-planar structures. The feasibility of attaining desired phase control (focusing or beam shifting) while simultaneously preserving the local resonance conditions is demonstrated analytically and simulated numerically.

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